
**Surface chemical analysis —
Secondary ion mass spectrometry
— Correction method for saturated
intensity in single ion counting
dynamic secondary ion mass
spectrometry**

*Analyse chimique des surfaces — Spectrométrie de masse des ions
secondaires — Méthode de correction de l'intensité de saturation en
SIMS dynamique à comptage d'ions individuel*

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ISO copyright office
CP 401 • Ch. de Blandonnet 8
CH-1214 Vernier, Geneva
Phone: +41 22 749 01 11
Fax: +41 22 749 09 47
Email: copyright@iso.org
Website: www.iso.org

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Contents

Page

Foreword	iv
Introduction	v
1 Scope	1
2 Normative references	1
3 Terms and definitions	1
4 Symbols and abbreviated terms	2
5 Outline of method	3
6 Procedure for evaluating intensity linearity	5
6.1 Obtaining reference sample.....	5
6.2 Setting the sample.....	5
6.3 Operating the instrument.....	5
6.3.1 Setting the ion beam and the mass analyser.....	5
6.3.2 Setting the charge compensation.....	5
6.3.3 Setting the ion detector.....	5
6.4 Acquiring the data.....	5
6.5 Assessing the linearity without and with intensity correction.....	6
6.5.1 Interpolating the minor isotope intensity.....	6
6.5.2 Correcting the ratio of the isotope abundance to the instrument transmittance.....	7
6.5.3 Assessing the linearity of intensity.....	8
6.5.4 Correcting the saturated intensity.....	8
6.5.5 Assessing the uncertainty of the data.....	11
7 Reporting the results	12
8 Correcting saturated intensity to the measurement results of the analysis samples	12
Annex A (informative) Effect of the dead time correction with various instruments for VAMAS study	13
Bibliography	15

Foreword

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